

Development of New 3d Si Detectors at BNL and CNM*

Z. Li¹, W. Chen¹, Y.H. Guo¹, D. Lissauer¹, D. Lynn¹, V. Radeka¹, M. Lozano², G. Pellegrini²

¹Brookhaven National Laboratory, Upton, NY 11973-5000, USA ² Centro Nacional de Microelectrónica, Campus Universidad Autónoma de Barcelona, 08193 Bellaterra (Barcelona), Spain

June 25, 2006

*This research was supported by the U.S. Department of Energy: Contract No. DE-AC02-98CH10886.

OUTLINE

o Introduction

o New 3d Structures

- o One-sided processing
- o Planar and 3d technologies
- o 2-column and 1-column possibilities
- o 3d stripixel configurations
- **o Processing aspects**
- **o** System aspects
- Photos of partially processed 1-column 3d stripixel detectors
- **o** Summary

Introduction

- For SLHC, one of the main issue is the radiation hardness for inner most detectors
- At fluence of 10¹⁶ n_{eq}/cm², the limiting factor for CCE is trapping of charges by radiation induced trap levels:
 - O Average trapping time: τ_{tr}= (5x10⁻⁷cm²/s × 10¹⁶ n_{eq}/cm²)⁻¹= 0.2 ns (H.W. Kraner et al, NIM A326 (1993) 350-356)
 - Charge collection distance: $d_{cce} \leq V_s \times \tau_{tr} = 20 \ \mu m!$
- o For planar detectors of >100 μm thickness, most volume is dead space even if fully depleted!
- 3d detectors decouples the detector thickness (d) and depletion depth (W) (i.e. the pitch (P) of p and n electrodes)

Standard 3d Si detectors

Schematics of a 3d detector (3d in terms of processing)



o 3d processing

- o 2-sided process
- Read out only p or n electrodes

Sherwood I. Parker et al., UH 511-959-00

Comparisons between planar and 3d pixel detectors

Planar

3d

- Easy processing (planar or 2d technology) 0
- Low leakage current 0
- **Good electric field profile** 0
- Not radiation hard at SLHC fluences 0
 - High full depletion voltages (thousands of volts)
 - Less sensitive volume: $d_{cce} \ll W \leq d$ (small CCE)

- **Radiation hard for SLHC fluences** 0
 - o small full depletion voltages (10-100 volts)
 - Deplétion and charge drift distance independent on thickness *d*
 - Whole volume sensitive: $d_{cce} \sim P=W$ (large CCE) Complicated processing (3d technology)
- 0
- High leakage current 0
- Abnormal electric field profile (low field 0 regions)

New 3d Structures

- Planar + 3d (we call it P+3d) processing technology
- o Dual-column or 1-column etching and doping possible
- o True single sided processing (no processing at all on the back side, different from ITC's 3DSTC detectors)
- Pixel, strip, and 2d stripixel configurations possible depending on electrode connections
- o No support wafer

Dual-column P+3d detector

- Both type of electrodes through holes etched into Si (p⁺ and n⁺)
- Each type of electrode columns in a pixel cell are connected by planar implantation of the same type
- No back side processing easier than the standard 3d technology
- o Good electric field distribution
- o Small depletion voltage
- o significant improvement on CCE at SLHC fluence as compared to planar detectors



Schematic of 1/2 of a single Cell



1-column P+3d detector



Schematic of 1/2 of a single Cell



 p⁺ here comes naturally from the isolation ring The two types of the P+3d detectors can be connected to form a

- 2d stripixel detector: 3d stripixel detector Electrons automatically go to the n⁺ electrodes (X-strip), and holes go to the p⁺ electrode (Y-strip)--- 1-sided 2d position sensitive detector 0 (2d)
- o No charge loss and much less capacitance as compared to the standard stripixel detector
- Can serve as a detector between pixel (true 2d) and single-sided strip 0 (1d)



o Single-column processing is much easier than 2-column Half of the work of hole etching and doping Not many processing labs can do doping of both types (UH and Glasgow)

o P-type substrates a natural choice:

No inversion or double junctions to worry about upon radiation

The area under oxide is naturally inverted, providing a depletion region

o Our new P+3d detectors can be processed just like planar detectors after the first few steps of column etching and doping

o BNL and CNM are now collaborating to produce 1-column P+3d detectors, n⁺ columns etched and doped (no column filling)

o First prototype detectors will be ready in a few months

System Aspects

o For pixel detectors, the size of the bump-bonding pads is an issue: >10 μ m.

o Options to chose from for different regions:

Region	25-50 cm	15-25 cm	7-15 cm		
Radiation level	$10^{14} - 10^{15} \text{ n}^{\text{eq}}/\text{cm}^2$	$\sim 10^{15} \mathrm{n}^{\mathrm{eq}}/\mathrm{cm}^2$	$\sim 10^{16} \mathrm{n^{eq}/cm^2}$		
Occupancy requirement	80 μm × 2-3 cm	50 μm × 400 μm	50 µm × 300 µm		
Detector type	Short strip and 2d stripixel	Pixel	Pixel		
Radiation hardness requirement	Short strip and 2d stripixel	Pixel	3d pixel or replacing every 2 years		
Overall detector type	Short strip and 2d stripixel	Pixel	3d pixel or replacing every 2 years		

Processing of Single Column 3d Stripixel Detectors

- Mask set has been designed and made
- Processing has begun, and n⁺ columns have been etched and doped at CNM in Barcelona, Spain
- The remaining planar processing is now going on at BNL
- First prototype single column 3d stripixel detectors will be ready for testing in September



Schematics for the new 3d stripixel detectors



Schematics for the new 3d stripixel detectors



Schematics for detector design x- strips



Schematics for detector design u- strips



Photos of detectors in the processing

			1mm					
STATE OF				Anter a second s	1110	11	1000	13.00
Statute .				(23		
the second								100
Conception in the	CONTRACTOR OF THE OWNER			Correction of the second				
The second	CONTRACTOR OF THE ADDRESS OF THE OWNER	*****	***************************************			0.01		
and the second	TREPORTER AND		***************************************			0.01		
andered.	Service and the service of the servi			- Manual Contraction of the second	1			
******	(TERROTAL STATES OF STATES			Constanting in the second seco				
STATES.								
TTATES.								
COLUMN T		Contraction of the second seco		11/***********************************				
Second Contents				Treesewassessessessessessessessesses				
		***************************************		CONTRACTOR CONTRACTOR CONTRACTOR				
		***************************************	AND DESCRIPTION OF THE OWNER OF THE OWNER.					
		***************************************		Conservation and the second se	1	188		
		***************************************		(**************************************				
		Contraction of the second second second		(and a subscription of the subscription of th				
*******				(**************************************				

	Caracteristic		STRACT AND ADDRESS OF THE PARTY					
*******			CONTRACTOR OF THE PARTY OF THE	***************************************		101		
-		Sector Contraction of the sector of the sect	······································	WITCHIER CONTRACTOR CONTRACTOR				
*******		COLUMN TRANSPORTATION AND ADDRESS						
		AND A CONTRACTOR AND A CONTRACT AND A CONTRACTACT AND A CONTRACT AND A CONTRACTACT AND A CONTRACT AND A CONTRACTACT AND A CONTRACTACTACTACTACTACTA	CONTRACTOR OF CONTRACTOR DESIGNATION OF CONTRACT	(entranticerererenterenterenterenterent				
		***************************************	(CONTRACTOR OF A CONTRACTOR OF A CONTRACT OF A CON					
		CONCERNMENT CONCERNMENT CONTRACTOR		***************************************				

			**********	*********				
			***************************************	Transferrance and the second s				
-			40000000000000000000000000000000000000	***********				
				(*************************************				
		And the second s	"	(**************************************				
	(and the second s			*********************************				
	-		(TELEVISION CONTRACTOR OF THE OWNER	************************************				
				(And the second				
*******	Commences and a second							
ABRICATE				************************************				

and other				***************************************				
		CONTRACTOR DE CO		ATTACATOR AND A A A A A A A A A A A A A A A A A A				
	WHEN PROPERTY AND ADDRESS OF ADDR			AND ADDRESS AND ADDRES				
	A REAL PROPERTY AND A REAL							
deres a		Constant of the second s		(ARCHARTSCHILLESS CONTRACTOR CONTRACTOR				
and the second	THE OWNER OF THE OWNER	AND THE OWNER OF THE OWNER OWNER OF THE OWNER		ARE ALL AND A ARE AND A ARE AN ARE AND A				
and a state of	and an	Canal and an other statement of the second statement o						
Contraction in the local division in the loc		the second s		A REAL PROPERTY AND A REAL				



n⁺ columns: 10 μm diameter, 240 μm deep (300 μm thickness)



Test Structures:

500 µm pitch, n⁺ region: 50 µm x 50 µm,





Summary

o New 3d Structures have been proposed

- Design and processing of new 3d detectors have begun
 - o 1-column 3d detectors
 - o One-sided processing with 2d sensitivity
 - o Planar and 3d technologies
 - o n⁺ columns have been etched and doped at CNM
 - The remaining planar processing are under way at BNL

First prototype detectors will be available in 2 months